

Notice of References Cited

Application/Control No.

09/852,612

Applicant(s)/Patent Under
Reexamination
ARATANI ET AL.

Examiner

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Art Unit

2614

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,373,503	04-2002	Perkes, Ronald M.	715/718
X	B	US-6,757,912	06-2004	Vaughan et al.	725/139
X	C	US-6,724,351	04-2004	Boger, Robert A.	345/3.2
X	D	US-6,285,406	09-2001	Brusky, Kevin J.	348/552
X	E	US-6,200,212	03-2001	Henry et al.	452/194
X	F	US-6,104,390	08-2000	Sturgeon et al.	715/718
X	G	US-6,037,994	03-2000	Bae, Sang Geun	348/510
X	H	US-6,005,550	12-1999	Vaughan et al.	345/157
X	I	US-5,926,174	07-1999	Shibamiya et al.	345/213
X	J	US-5,819,156	10-1998	Belmont, Brian V.	725/14
X	K	US-6,037,994	03-2000	Bae, Sang Geun	348/510
X	L	US-5,819,156	10-1998	Belmont, Brian V.	725/14
X	M	US-5,850,340	12-1998	York, Matthew	700/83

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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